

## PROBE FOR TESTER

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- **International:** G01R1/06; G01R1/06; (IPC1-7): G01R1/06  
- **europaean:**  
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### Abstract of JP53037077

**PURPOSE:**To enable to check the bad contact and to decrease the error of measurement, by contacting the probe for tester, provided the forcing needle and sensing needle, with the material to be measured by kelvin contact.

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